

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	1	"20040260502".pn.	US-PGPUB	OR	OFF	2005/04/28 07:09
S2	64	((integrated adj circuit) ic semi\$conductor wafer chip lsi microprocessor microcomputer) with testing) and (bist (built adj in adj self adj test) (scan adj (test testing))) and (hash adj function)	US-PGPUB	OR	ON	2005/04/27 14:53
S3	33	((integrated adj circuit) ic semi\$conductor wafer chip lsi microprocessor microcomputer) with testing) and (bist (built adj in adj self adj test) (scan adj (test testing))) and (hash adj function)	USPAT	OR	ON	2005/04/21 13:43
S4	1	liu.in. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi microprocessor microcomputer) with testing) and (bist (built adj in adj self adj test) (scan adj (test testing))) and (hash adj function)	US-PGPUB; USPAT	OR	ON	2005/04/21 13:58
S5	2569	(hash adj function)	USPAT	OR	ON	2005/04/21 13:43
S6	755	(hash adj function) and (sha\$1 md5)	USPAT	OR	ON	2005/04/21 13:43
S7	36	(hash adj function) and (sha\$1 md5) and (bist (built adj in adj self adj test) (scan adj (test testing)))	USPAT	OR	ON	2005/04/21 13:56
S8	0	((ic (integrated adj circuit) semi\$conductor) near3 testing) and (hash adj function) and (sha\$1 md5) and (bist (built adj in adj self adj test) (scan adj (test testing)))	USPAT	OR	ON	2005/04/21 13:45
S9	0	(hash adj function) and (sha\$1 md5) and (bist (built adj in adj self adj test) (scan adj (test testing))) and (test adj (message communication information data signal) adj (digest summary))	USPAT	OR	ON	2005/04/21 13:59
S10	1	(hash adj function) and (sha\$1 md5) and (bist (built adj in adj self adj test) (scan adj (test testing))) and (test adj (message communication information data signal) adj (digest summary))	US-PGPUB	OR	ON	2005/04/21 13:57
S11	1	liu.in. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi microprocessor microcomputer) with testing) and (bist (built adj in adj self adj test) (scan adj (test testing))) and (hash adj function)	EPO; JPO; DERWENT	OR	ON	2005/04/21 13:58
S12	129	(hash adj function) and (sha\$1 md5) and (atm (accelerated adj test adj method) bist (built adj in adj self adj test) (scan adj (test testing)))	USPAT	OR	ON	2005/04/21 14:00

S13	31	(hash adj function) and (sha\$1 md5) and (atm (accelerated adj test adj method) bist (built adj in adj self adj test) (scan adj (test testing))) and (((integrated adj circuit) ic semi\$conductor wafer chip lsi microprocessor microcomputer) with testing) and (bist (built adj in adj self adj test) (scan adj (test testing)))	USPAT	OR	ON	2005/04/21 14:07
S14	1	(test adj vector adj data) and (test adj message adj digest) and (hash adj function)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 14:08
S15	6649	(hash adj function)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 14:10
S16	9	(hash adj function) and (test adj (signal data message communication information) adj (digest summary report))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 15:15
S17	2	(hash adj function) and (test adj (signal data message communication information) adj (digest summary report)) and ((test adj (data signal information)) (test adj vector adj (data signal information)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 14:13
S18	1	(hash adj function) and (test adj (signal data message communication information) adj (digest summary report)) and ((standard adj message) (golden adj signature))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 14:16
S19	4739	(ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and (atm (accelerated adj test adj method)) and ((hash adj function) sha\$1 md5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 15:28

S20	3	(ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and (atm (accelerated adj test adj method)) and ((hash adj function) sha\$1 md5) and (((test analysis) adj (message communication data information word sample segment) adj (summary digest report)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 15:26
S21	3	(ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and (atm (accelerated adj test adj method)) and ((hash adj function) sha\$1 md5) and (((test analysis) adj (message communication data information word sample segment) adj (summary digest report))) and (((standard reference) adj (message communication data information word sample segment)) (golden adj signature))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 15:28
S22	205	(ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and (atm (accelerated adj test adj method)) and ((hash adj function) sha\$1 md5) and (((standard reference) adj (message communication data information word sample segment)) (golden adj signature))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 15:30
S23	2	(ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and ((accelerated adj test adj method)) and ((hash adj function) "sha-1" md5) and (((standard reference) adj (message communication data information word sample segment)) (golden adj signature))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 15:30
S24	2	(ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and ((accelerated adj test adj method)) and ((hash adj function) "sha-1" md5)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 15:30

S25	42	(ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and ((accelerated adj test adj method)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 15:32
S26	2	(ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and ((accelerated adj test adj method))) and (hash adj function)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 15:32
S27	2	(ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and ((accelerated adj test adj method))) and hash	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 15:32
S28	6649	hash adj function	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 15:33
S29	508	(hash adj function) and "sha-1" and md5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 15:34
S30	362	(ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and (hash adj function) and "sha-1" and md5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 15:36
S31	1	(ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and (hash adj function) and "sha-1" and md5 and ((accelerated adj test adj (method procedure process methodology routine algorithm program)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 15:35
S32	362	(ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and (hash adj function) and "sha-1" and "md5"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 15:36

S33	9	(ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and (hash adj function) and "sha-1" and "md5" and ((standard reference golden) adj (message signature))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/21 15:36
S34	98	((((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) with testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and ((hash "sha-1" md5 sha\$1) adj function)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 09:19
S35	2	((((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 (testing evaluation analysis)) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice))) and ((hash "sha-1" md5 sha\$1) adj function)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 07:26
S37	2962	((((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 07:56
S38	5	((((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (((standard reference) adj (message communication) adj (digest report)) (golden adj signature))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 08:06

S39	1	(((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (((standard reference) adj (message communication) adj (digest report)) (golden adj signature)) and ((hash transform) adj function)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 08:06
S40	98	(((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and ((hash transform) adj function)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 08:07
S41	12	("6021514" "6125465" "4779273" "6516432" "5574733" "4377757" "5247525" "5412665" "6738939" "20020073373" "20020059547" "20040003330").pn.	US-PGPUB; USPAT	OR	ON	2005/04/25 08:09
S42	0	("6021514" "6125465" "4779273" "6516432" "5574733" "4377757" "5247525" "5412665" "6738939" "20020073373" "20020059547" "20040003330").pn. and ((hash sha\$1 md5 transform "sha-1") adj function)	US-PGPUB; USPAT	OR	ON	2005/04/25 08:10
S44	1	(test adj vector adj data) and (test adj message adj digest) and (standard adj message adj digest) and (response adj data) and (hash)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 08:12
S45	2962	(((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 08:14

S46	834	(((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (test near3 vector)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 08:14
S47	432	(((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (test near3 vector) and (response near3 (data signal information))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 08:14
S48	4	(((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (test near3 vector) and (response near3 (data signal information)) and (test near3 message)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 08:17
S49	2	(((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (test near3 vector) and hash and (test near3 message)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 08:19

S50	22	(((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice))) with (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 08:19
S51	2	(((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice))) with (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing)) and (hash "sha-1" sha\$1 md5 shax)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 08:20
S52	1	(((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice))) with (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing)) and ((test standard golden protocol prototypical) near3 (message communication vector data information) near3 (digest report summary))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 08:23
S53	3	(((accelerated accelerate acceleration autonomous automated automatic self bist (built adj self adj test)) near3 (test testing) near3 (method methodology procedure routine algorithm process way step practice))) with (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 (test testing))) and ((test standard golden protocol prototypical) near3 (message communication vector data information) near3 (digest report summary))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 08:27

S54	3	(((((accelerated accelerate acceleration autonomous automated automatic self bist (built adj self adj test)) near3 (test testing) near3 (method methodology procedure routine algorithm process way step practice)))) with (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 (test testing))) and (hash near3 (function module section part component)))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 08:28
S55	254	324/500.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 12:52
S56	1053	324/537.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:42
S57	2792	324/765.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:42
S58	320	702/108.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:42
S59	97	702/109.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:42
S60	542	702/117.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:43
S61	222	702/118.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:42
S62	202	702/120.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:43
S63	368	714/1.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:43
S64	962	714/25.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:43
S65	1295	714/718.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:43
S66	514	714/719.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:43
S67	774	714/726.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:43
S68	236	714/732.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:43
S69	8	702/117.ccls. and 324/500.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:45
S70	11	702/117.ccls. and 324/537.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:51
S71	36	702/117.ccls. and 324/765.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:52
S72	28	702/117.ccls. and 702/108.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:44

S73	2	702/117.ccls. and 702/109.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:44
S74	45	702/117.ccls. and 702/118.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:44
S75	35	702/117.ccls. and 702/120.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:44
S76	0	702/117.ccls. and 714/1.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:44
S77	10	702/117.ccls. and 714/25.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:45
S78	15	702/117.ccls. and 714/718.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:45
S79	3	702/117.ccls. and 714/719.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:45
S80	9	702/117.ccls. and 714/726.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:45
S81	5	702/117.ccls. and 714/732.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 08:45
S82	0	702/117.ccls. and 324/500.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function)	US-PGPUB; USPAT	OR	ON	2005/04/25 08:46
S83	0	702/117.ccls. and 324/537.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function)	US-PGPUB; USPAT	OR	ON	2005/04/25 08:46
S84	0	702/117.ccls. and 324/765.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function)	US-PGPUB; USPAT	OR	ON	2005/04/25 08:46
S85	0	702/117.ccls. and 702/108.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function)	US-PGPUB; USPAT	OR	ON	2005/04/25 08:46
S86	0	702/117.ccls. and 702/109.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function)	US-PGPUB; USPAT	OR	ON	2005/04/25 08:47
S87	1	702/117.ccls. and 702/118.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function)	US-PGPUB; USPAT	OR	ON	2005/04/25 08:48
S88	1	702/117.ccls. and 702/120.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function)	US-PGPUB; USPAT	OR	ON	2005/04/25 08:48
S89	0	702/117.ccls. and 714/1.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function)	US-PGPUB; USPAT	OR	ON	2005/04/25 08:47
S90	0	702/117.ccls. and 714/25.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function)	US-PGPUB; USPAT	OR	ON	2005/04/25 08:47
S91	0	702/117.ccls. and 714/718.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function)	US-PGPUB; USPAT	OR	ON	2005/04/25 08:47

S92	0	702/117.ccls. and 714/719.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function)	US-PGPUB; USPAT	OR	ON	2005/04/25 08:47
S93	0	702/117.ccls. and 714/726.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function)	US-PGPUB; USPAT	OR	ON	2005/04/25 08:47
S94	1	702/117.ccls. and 714/732.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function)	US-PGPUB; USPAT	OR	ON	2005/04/25 08:47
S95	4	("5450326" "5991699" "6289292" "6336086").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/04/25 08:50
S96	4	("6507800").URPN.	USPAT	OR	OFF	2005/04/25 08:50
S97	6	324/500.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 09:10
S98	25	324/537.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 09:09
S99	173	324/765.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 08:52

S100	4	702/108.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 08:53
S101	0	702/109.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 08:53
S102	39	702/117.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 08:53
S103	18	702/118.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 08:53
S104	20	702/120.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 08:53

S105	98	"702"/\$.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 08:53
S106	390	"324"/\$.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 08:53
S107	39	"713"/\$.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 08:53
S108	1363	"714"/\$.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 08:53
S109	1	714/1.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 08:54

S110	19	714/25.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 08:54
S111	139	714/718.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 08:54
S112	42	714/719.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 08:54
S113	324	714/726.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 08:54
S114	47	714/732.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))))	US-PGPUB; USPAT	OR	ON	2005/04/25 08:54

S115	0	324/500.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1"))	US-PGPUB; USPAT	OR	ON	2005/04/25 09:10
S116	0	324/537.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1"))	US-PGPUB; USPAT	OR	ON	2005/04/25 09:10
S117	4	324/765.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1"))	US-PGPUB; USPAT	OR	ON	2005/04/25 09:12
S118	0	702/108.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1"))	US-PGPUB; USPAT	OR	ON	2005/04/25 09:10

S119	0	702/109.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing)))) and (hash md5 sha\$1 "sha-1")	US-PGPUB; USPAT	OR	ON	2005/04/25 09:11
S120	5	702/117.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing)))) and (hash md5 sha\$1 "sha-1")	US-PGPUB; USPAT	OR	ON	2005/04/25 09:13
S121	0	702/118.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing)))) and (hash md5 sha\$1 "sha-1")	US-PGPUB; USPAT	OR	ON	2005/04/25 09:11
S122	4	702/120.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing)))) and (hash md5 sha\$1 "sha-1")	US-PGPUB; USPAT	OR	ON	2005/04/25 09:14

S123	1	714/1.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing)))) and (hash md5 sha\$1 "sha-1")	US-PGPUB; USPAT	OR	ON	2005/04/25 09:12
S124	0	714/25ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing)))) and (hash md5 sha\$1 "sha-1")	US-PGPUB; USPAT	OR	ON	2005/04/25 09:11
S125	0	714/718ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing)))) and (hash md5 sha\$1 "sha-1")	US-PGPUB; USPAT	OR	ON	2005/04/25 09:11
S126	0	714/719ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing)))) and (hash md5 sha\$1 "sha-1")	US-PGPUB; USPAT	OR	ON	2005/04/25 09:11

S127	0	714/726ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1"))	US-PGPUB; USPAT	OR	ON	2005/04/25 09:12
S128	0	714/732ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1"))	US-PGPUB; USPAT	OR	ON	2005/04/25 09:12
S129	114	((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((hash "sha-1" md5) adj function)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/25 09:21
S130	601	324/763.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 12:53
S131	49	324/764.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 12:52
S132	2792	324/765.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 12:52
S133	171	324/766.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 12:52
S134	309	324/767.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 12:53
S135	107	324/768.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/25 12:53
S136	0	324/763.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((hash "sha-1" md5) adj function)	US-PGPUB; USPAT	OR	ON	2005/04/25 13:06
S137	0	324/764.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((hash "sha-1" md5) adj function)	US-PGPUB; USPAT	OR	ON	2005/04/25 12:53
S138	0	324/765.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((hash "sha-1" md5) adj function)	US-PGPUB; USPAT	OR	ON	2005/04/25 12:53

S139	0	324/766.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((hash "sha-1" md5) adj function)	US-PGPUB; USPAT	OR	ON	2005/04/25 12:53
S140	0	324/767.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((hash "sha-1" md5) adj function)	US-PGPUB; USPAT	OR	ON	2005/04/25 12:54
S141	0	324/768.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((hash "sha-1" md5) adj function)	US-PGPUB; USPAT	OR	ON	2005/04/25 12:54
S142	13	702/117.ccls. and 324/763.ccls.	US-PGPUB; USPAT	OR	ON	2005/04/25 12:54
S143	0	702/117.ccls. and 324/764.ccls.	US-PGPUB; USPAT	OR	ON	2005/04/25 12:54
S144	36	702/117.ccls. and 324/765.ccls.	US-PGPUB; USPAT	OR	ON	2005/04/25 12:55
S145	0	702/117.ccls. and 324/766.ccls.	US-PGPUB; USPAT	OR	ON	2005/04/25 12:54
S146	0	702/117.ccls. and 324/767.ccls.	US-PGPUB; USPAT	OR	ON	2005/04/25 12:54
S147	0	702/117.ccls. and 324/768.ccls.	US-PGPUB; USPAT	OR	ON	2005/04/25 12:54
S148	0	702/117.ccls. and 324/765.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((hash "sha-1" md5) adj function)	US-PGPUB; USPAT	OR	ON	2005/04/25 12:55
S149	0	702/117.ccls. and 324/765.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((compare comparing comparison verify verifying verification) with ((transform "sha-1" md5 hash) near3 (output result product)) with ((standard prototype prototypical golden reference) near3 (message signature digest report word)))	US-PGPUB; USPAT	OR	ON	2005/04/25 12:59
S150	0	((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((compare comparing comparison verify verifying verification) with ((transform "sha-1" md5 hash) near3 (output result product)) with ((standard prototype prototypical golden reference) near3 (message signature digest report word)))	US-PGPUB; USPAT	OR	ON	2005/04/25 13:00
S151	0	((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((compare comparing comparison verify verifying verification) with ((transform "sha-1" md5 hash) near3 (output result product)) with ((standard prototype prototypical golden reference) near3 (message signature digest report word)))	USOCR; IBM_TDB	OR	ON	2005/04/25 13:00

S152	0	((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((compare comparing comparison verify verifying verification) with ((transform "sha-1" md5 hash) near3 (output result product)) with ((standard prototype prototypical golden reference) near3 (message signature digest report word)))	EPO; JPO; DERWENT	OR	ON	2005/04/25 13:00
S153	31	((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((compare comparing comparison verify verifying verification) with ((standard prototype prototypical golden reference) near3 (message signature digest report word)))	US-PGPUB; USPAT	OR	ON	2005/04/25 13:03
S154	3	((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((shorten concatenate concatenation transform) with (response result resultant)) and ((compare comparing comparison verify verifying verification) with ((standard prototype prototypical golden reference) near3 (message signature digest report word)))	US-PGPUB; USPAT	OR	ON	2005/04/25 13:05
S155	60	324/763.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test))	US-PGPUB; USPAT	OR	ON	2005/04/25 13:08
S156	1	324/764.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test))	US-PGPUB; USPAT	OR	ON	2005/04/25 13:07
S157	154	324/765.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test))	US-PGPUB; USPAT	OR	ON	2005/04/25 13:13
S158	1	324/766.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test))	US-PGPUB; USPAT	OR	ON	2005/04/25 13:07
S159	2	324/767.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test))	US-PGPUB; USPAT	OR	ON	2005/04/25 13:07
S160	1	324/768.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test))	US-PGPUB; USPAT	OR	ON	2005/04/25 13:07
S161	1	((accelerated adj (test testing)) bist (built adj in adj self adj test)) and (ic (integrated adj circuit) (semiconductor near3 (wafer die dice chip component))) and ((test testing input) near3 vector near3 (data signal information communication message)) and ((response result resultant) near3 (data signal information communication message)) and (hash "sha-1" md5 (transform near3 function)) and ((test testing response result resultant) near3 (data signal information communication message) near3 (digest report summary)) and ((standard reference prototype prototypical golden) near3 (data signal information communication message) near3 (digest report summary))	US-PGPUB; USPAT	OR	ON	2005/04/25 13:22

S162	0	((accelerated adj (test testing)) bist (built adj in adj self adj test)) and (ic (integrated adj circuit) (semiconductor near3 (wafer die dice chip component))) and ((test testing input) near3 vector near3 (data signal information communication message)) and ((response result resultant) near3 (data signal information communication message)) and (hash "sha-1" md5 (transform near3 function)) and ((test testing response result resultant) near3 (data signal information communication message) near3 (digest report summary)) and ((standard reference prototype prototypical golden) near3 (data signal information communication message) near3 (digest report summary))	USOCR; IBM_TDB	OR	ON	2005/04/25 13:21
S163	0	((accelerated adj (test testing)) bist (built adj in adj self adj test)) and (ic (integrated adj circuit) (semiconductor near3 (wafer die dice chip component))) and ((test testing input) near3 vector near3 (data signal information communication message)) and ((response result resultant) near3 (data signal information communication message)) and (hash "sha-1" md5 (transform near3 function)) and ((test testing response result resultant) near3 (data signal information communication message) near3 (digest report summary)) and ((standard reference prototype prototypical golden) near3 (data signal information communication message) near3 (digest report summary))	EPO; JPO; DERWENT	OR	ON	2005/04/25 13:21
S164	1	((ic (integrated adj circuit) (semiconductor near3 (wafer die dice chip component))) with (accelerated adj (test testing))) and ((test testing input) near3 vector near3 (data signal information communication message)) and ((response result resultant) near3 (data signal information communication message)) and ((standard reference prototype prototypical golden) near3 (data signal information communication message) near3 (digest report summary))	US-PGPUB; USPAT	OR	ON	2005/04/25 13:25
S165	0	((ic (integrated adj circuit) (semiconductor near3 (wafer die dice chip component))) with (accelerated adj (test testing))) and ((test testing input) near3 vector near3 (data signal information communication message)) and ((response result resultant) near3 (data signal information communication message)) and ((standard reference prototype prototypical golden) near3 (data signal information communication message) near3 (digest report summary))	USOCR; IBM_TDB	OR	ON	2005/04/25 13:25

S166	0	((ic (integrated adj circuit) (semiconductor near3 (wafer die dice chip component))) with (accelerated adj (test testing))) and ((test testing input) near3 vector near3 (data signal information communication message)) and ((response result resultant) near3 (data signal information communication message)) and ((standard reference prototype prototypical golden) near3 (data signal information communication message) near3 (digest report summary)))	EPO; JPO; DERWENT	OR	ON	2005/04/25 13:25
S167	1292	713/176.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:44
S168	143	713/179.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:41
S169	256	713/180.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:41
S170	233	713/181.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:41
S171	998	713/193.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:41
S172	276	713/194.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:42
S173	1400	714/724.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:42
S174	757	714/733.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:42
S175	350	714/734.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:42
S176	258	714/735.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:42
S177	667	714/736.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:42
S178	80	714/737.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:42
S179	0	702/117.ccls. and 713/176.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:43
S180	0	702/117.ccls. and 713/179.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:43
S181	0	702/117.ccls. and 713/180.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:43
S182	0	702/117.ccls. and 713/181.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:43
S183	0	702/117.ccls. and 713/193.ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:43
S184	0	702/117.ccls. and 713/194ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:43
S185	0	702/117.ccls. and 714/724ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:43

S186	0	702/117.ccls. and 714/733ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:43
S187	0	702/117.ccls. and 714/734ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:43
S188	0	702/117.ccls. and 714/735ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:44
S189	0	702/117.ccls. and 714/736ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:44
S190	0	702/117.ccls. and 714/737ccls.	US-PGPUB; USPAT	OR	OFF	2005/04/27 08:44
S191	5	713/176.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5)	US-PGPUB; USPAT	OR	ON	2005/04/27 08:53
S192	3	713/176.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature))	US-PGPUB; USPAT	OR	ON	2005/04/27 08:55
S193	0	713/179.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature))	US-PGPUB; USPAT	OR	ON	2005/04/27 08:55
S194	1	713/180.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature))	US-PGPUB; USPAT	OR	ON	2005/04/27 08:57
S195	1	713/181.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature))	US-PGPUB; USPAT	OR	ON	2005/04/27 08:58

S196	1	713/193.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature))	US-PGPUB; USPAT	OR	ON	2005/04/27 08:58
S197	1	713/194.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature))	US-PGPUB; USPAT	OR	ON	2005/04/27 08:58
S198	0	714/724.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature))	US-PGPUB; USPAT	OR	ON	2005/04/27 08:58
S199	0	714/733.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature))	US-PGPUB; USPAT	OR	ON	2005/04/27 08:58
S200	0	714/734.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature))	US-PGPUB; USPAT	OR	ON	2005/04/27 08:58
S201	0	714/735.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature))	US-PGPUB; USPAT	OR	ON	2005/04/27 08:58
S202	0	714/736.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature))	US-PGPUB; USPAT	OR	ON	2005/04/27 08:59

S203	0	714/737.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature))	US-PGPUB; USPAT	OR	ON	2005/04/27 08:59
S204	133	((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature))	US-PGPUB; USPAT	OR	ON	2005/04/27 09:07
S205	122	((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) and (ip (intellectual adj property))	US-PGPUB; USPAT	OR	ON	2005/04/27 09:07
S206	0	((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) and (ip (intellectual adj property))	USOCR; IBM_TDB	OR	ON	2005/04/27 09:08
S207	0	((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) and (ip (intellectual adj property))	EPO; JPO; DERWENT	OR	ON	2005/04/27 09:08
S208	1	((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature))	EPO; JPO; DERWENT	OR	ON	2005/04/27 09:08

S209	0	((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)))	USOCR; IBM_TDB	OR	ON	2005/04/27 09:28
S210	0	((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and ((compare comparing comparison match matching correlate correlating correlation compared matched correlated) with ((hash "sha-1" md5) near3 (result resultant output transform)) with ((standard reference gold golden) near3 (message word signature))))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/27 12:32
S211	2	("20040664457" "20020138802" "6507800" "6266771" "6757832" "6816968" "6374354" "6708273" "6442525" "6085321" "6795919").pn. and (input (test with vector with (data information))) and (hash "sha-1" md5) and ((test with (communication message) with (digest report)) output) and ((standard reference gold golden) adj (message signature word)) and (limit set\$point threshold (pre\$determined adj requirement))	US-PGPUB; USPAT	OR	ON	2005/04/27 10:02
S212	1	((((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5) and ((verify verifying verified verification compare compared comparing comparison) with ((standard reference gold golden) near3 (signature message data information digest report))))	US-PGPUB; USPAT	OR	ON	2005/04/27 12:44

S213	0	(((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5) and ((verify verifying verified verification compare compared comparing comparison) with ((standard reference gold golden) near3 (signature message data information digest report)))	USOCR; IBM_TDB	OR	ON	2005/04/27 12:50
S214	1	(((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5) and ((verify verifying verified verification compare compared comparing comparison) with ((standard reference gold golden) near3 (signature message data information digest report)))	EPO; JPO; DERWENT	OR	ON	2005/04/27 12:43
S215	16	(((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and ((verify verifying verified verification compare compared comparing comparison) with ((standard reference gold golden) near3 (signature message data information digest report)))	US-PGPUB; USPAT	OR	ON	2005/04/27 12:47
S216	0	(((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and ((verify verifying verified verification compare compared comparing comparison) with ((standard reference gold golden) near3 (signature message data information digest report)))	USOCR; IBM_TDB	OR	ON	2005/04/27 12:47

S217	2	((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and ((verify verifying verified verification compare compared comparing comparison) with ((standard reference gold golden) near3 (signature message data information digest report)))	DERWENT	OR	ON	2005/04/27 12:48
S218	0	((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and ((verify verifying verified verification compare compared comparing comparison) with ((standard reference gold golden) near3 (signature message data information digest report)))	EPO; JPO	OR	ON	2005/04/27 12:47
S219	0	((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5)	USOCR; IBM_TDB	OR	ON	2005/04/27 12:49
S220	1	((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5)	DERWENT	OR	ON	2005/04/27 12:49
S221	0	((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5)	EPO; JPO	OR	ON	2005/04/27 12:49
S222	3	((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5)	US-PGPUB; USPAT	OR	ON	2005/04/27 12:49

S223	0	(((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5) and (((standard reference gold golden) near3 (signature message data information digest report)))	USOCR; IBM_TDB	OR	ON	2005/04/27 12:50
S224	2	(((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5) and (((standard reference gold golden) near3 (signature message data information digest report)))	US-PGPUB; USPAT	OR	ON	2005/04/27 13:29
S225	13208	liu.in.	US-PGPUB; USPAT	OR	OFF	2005/04/27 13:28
S226	3	liu.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step))))	US-PGPUB; USPAT	OR	ON	2005/04/27 13:30
S227	26	silverbrook.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step))))	US-PGPUB; USPAT	OR	ON	2005/04/27 13:31
S228	1	silverbrook.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash hashing "sha-1" md5)	US-PGPUB; USPAT	OR	ON	2005/04/27 13:34

S229	0	walmsley.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step))))	US-PGPUB; USPAT	OR	ON	2005/04/27 13:32
S230	0	lapstun.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step))))	US-PGPUB; USPAT	OR	ON	2005/04/27 13:33
S231	0	sheu.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step))))	US-PGPUB; USPAT	OR	ON	2005/04/27 13:33
S232	2	house.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step))))	US-PGPUB; USPAT	OR	ON	2005/04/27 13:33
S233	1	siegel.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step))))	US-PGPUB; USPAT	OR	ON	2005/04/27 13:34
S234	51	williams.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step))))	US-PGPUB; USPAT	OR	ON	2005/04/27 13:34

S235	1	williams.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash hashing "sha-1" md5)	US-PGPUB; USPAT	OR	ON	2005/04/27 13:34
S236	1	(((integrated adj circuit) ic semiconductor wafer chip lsi vlsi) near3 testing) and ((hash hashing "sha-1" sha1 md5) adj (function transform)) and shax	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/27 14:56
S237	1	(((integrated adj circuit) ic semiconductor wafer chip lsi vlsi) near3 testing) and shax	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/27 14:56
S238	2	((hash hashing "sha-1" sha1 md5) adj (function transform)) and shax	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/27 14:58
S239	39	shax	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/04/27 14:58
S240	3	(shax (secure adj hash adj algorithm adj accelerator))	US-PGPUB; USPAT	OR	ON	2005/04/28 07:10
S241	34	(shax (secure adj hash adj algorithm adj accelerator))	USOCR; IBM_TDB	OR	ON	2005/04/28 07:26
S242	3	(shax (secure adj hash adj algorithm adj accelerator))	EPO; JPO; DERWENT	OR	ON	2005/04/28 07:10
S243	0	((ic (integrated adj circuit) wafer chip die semiconductor (semiconductor adj (wafer chip die))) with (test testing analysis calibrating calibration)) and ((shax (secure adj hash adj algorithm adj accelerator)))	USOCR; IBM_TDB	OR	ON	2005/04/28 07:14
S244	0	("6507800" "20040133831").pn. and (sha1 md5 shax "sha-1")	US-PGPUB; USPAT	OR	ON	2005/04/28 07:46

S245	126	(ic (integrated adj circuit) semiconductor wafer chip die (semiconductor adj (wafer chip die))) and ("sha-1" shax md5) and ((accelerated adj (test testing) adj (method procedure methodology process algorithm routine program)) (bist (built adj self adj test)) ((automated automatic) adj (test testing) adj (device equipment apparatus instrument module chip component circuit))))	US-PGPUB; USPAT	OR	ON	2005/04/28 10:25
S246	24	(ic (integrated adj circuit) semiconductor wafer chip die (semiconductor adj (wafer chip die))) and ("sha-1" shax md5) and ((accelerated adj (test testing) adj (method procedure methodology process algorithm routine program)) (bist (built adj self adj test)) ((automated automatic) adj (test testing) adj (device equipment apparatus instrument module chip component circuit)))) not (print printing camera imager)	US-PGPUB; USPAT	OR	ON	2005/04/28 11:12
S247	6	("4987595" "5557346" "5623545" "5631960" "5721777" "5832207").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/04/28 07:44
S248	1	("6704871").URPN.	USPAT	OR	OFF	2005/04/28 07:42
S250	1	(ic (integrated adj circuit) semiconductor wafer chip die (semiconductor adj (wafer chip die))) and ("sha-1" shax md5) and ((accelerated adj (test testing) adj (method procedure methodology process algorithm routine program)) (bist (built adj self adj test)) ((automated automatic) adj (test testing) adj (device equipment apparatus instrument module chip component circuit)))) and (shax (secure adj hash adj algorithm adj accelerator)) not (print printing camera imager)	US-PGPUB; USPAT	OR	ON	2005/04/28 07:43
S251	0	("6704871").URPN. and ("sha-1" shax md5) and (shax (secure adj hash adj algorithm adj accelerator))	USPAT	OR	ON	2005/04/28 07:43
S252	0	("4987595" "5557346" "5623545" "5631960" "5721777" "5832207").PN. and ("sha-1" shax md5) and (shax (secure adj hash adj algorithm adj accelerator))	US-PGPUB; USPAT; USOCR	OR	ON	2005/04/28 07:44
S253	1	"6507800".pn.	USPAT	OR	OFF	2005/04/28 07:46
S254	4	("5450326" "5991699" "6289292" "6336086").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/04/28 07:47
S255	4	("6507800").URPN.	USPAT	OR	OFF	2005/04/28 07:49
S256	0	("5450326" "5991699" "6289292" "6336086").PN. and ("sha-1" shax md5) (shax (secure adj hash adj algorithm adj accelerator))	US-PGPUB; USPAT; USOCR	OR	ON	2005/04/28 07:49

S257	0	("6507800").URPN. and (("sha-1" shax md5) (shax (secure adj hash adj algorithm adj accelerator))))	USPAT	OR	ON	2005/04/28 07:48
S258	0	("5450326" "5991699" "6289292" "6336086").PN. and (hash hashing)	US-PGPUB; USPAT; USOCR	OR	ON	2005/04/28 07:49
S259	0	("6507800").URPN. and (hash hashing)	USPAT	OR	OFF	2005/04/28 07:49
S265	45	(hash hashing) and (ip (intellectual adj property)) and (bist (built adj self adj test))	USPAT	OR	ON	2005/04/28 08:37
S266	3	(hash hashing) and (ip (intellectual adj property)) and (bist (built adj self adj test)) not (print printer printing camera imager)	USPAT	OR	ON	2005/04/28 08:37



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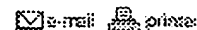
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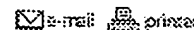


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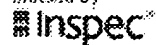
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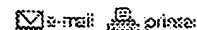




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